



UT25N04

Power MOSFET

25A, 40V N-CHANNEL POWER MOSFET

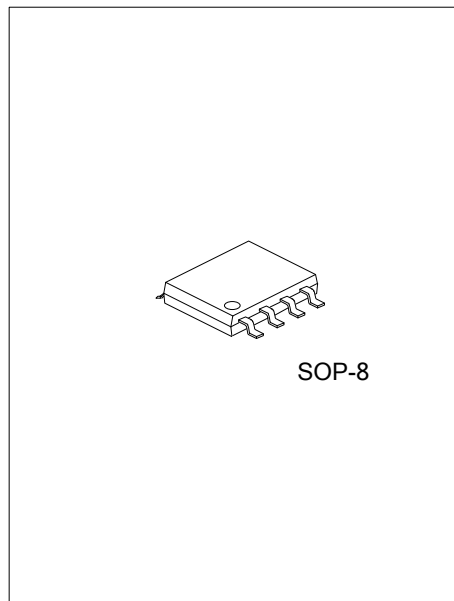
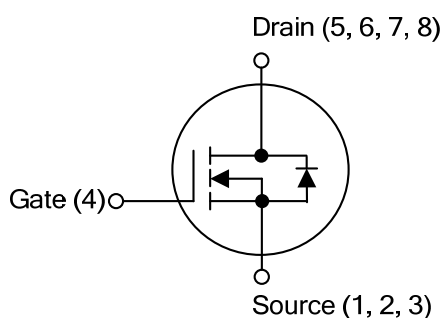
DESCRIPTION

The UTC **UT25N04** is a N-channel power MOSFET providing very low on-resistance. It has high efficiency and perfect cost-effectiveness. It can be generally applied in the commercial and industrial fields.

FEATURES

- * $R_{DS(ON)} \leq 20 \text{ m}\Omega$ @ $V_{GS} = 10\text{V}$, $I_D = 12.5\text{A}$
- $R_{DS(ON)} \leq 26 \text{ m}\Omega$ @ $V_{GS} = 4.5\text{V}$, $I_D = 12.5\text{A}$
- * Simple drive requirement

SYMBOL



SOP-8

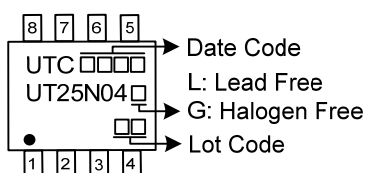
ORDERING INFORMATION

Ordering Number		Package	Pin Assignment								Packing
Lead Free	Halogen Free		1	2	3	4	5	6	7	8	
UT25N04L-S08-R	UT25N04G-S08-R	SOP-8	S	S	S	G	D	D	D	D	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

UT25N04G-S08-R		(1) Packing Type	(1) R: Tape Reel
		(2) Package Type	(2) S08: SOP-8
		(3) Green Package	(3) G: Halogen Free and Lead Free, L: Lead Free

MARKING



■ ABSOLUTE MAXIMUM RATING ($T_C=25^{\circ}\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	40	V
Gate-Source Voltage		V_{GSS}	± 12	V
Drain Current	Continuous	I_D	25	A
	Pulsed (Note 2)	I_{DM}	50	A
Avalanche Energy (Note 3)	Single Pulsed (Note 3)	E_{AS}	11	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	1.9	V/ns
Power Dissipation		P_D	1.7	W
Junction Temperature		T_J	+150	$^{\circ}\text{C}$
Storage Temperature Range		T_{STG}	-55 ~ +150	$^{\circ}\text{C}$

- Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.
 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
 3. $L = 0.1\text{mH}$, $I_{AS} = 15\text{A}$, $V_{DD} = 25\text{V}$, $R_G = 25\ \Omega$, Starting $T_J = 25^{\circ}\text{C}$.
 4. $I_{SD} \leq 25\text{A}$, $di/dt \leq 200\text{ A}/\mu\text{s}$, $V_{DD} \leq V_{(BR)DSS}$, $T_J = 25^{\circ}\text{C}$.

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	125	$^{\circ}\text{C}/\text{W}$
Junction to Case	θ_{JC}	73.5	$^{\circ}\text{C}/\text{W}$

Note: Device mounted on FR-4 substrate P_C board, 2oz copper, with 1inch square copper plate.

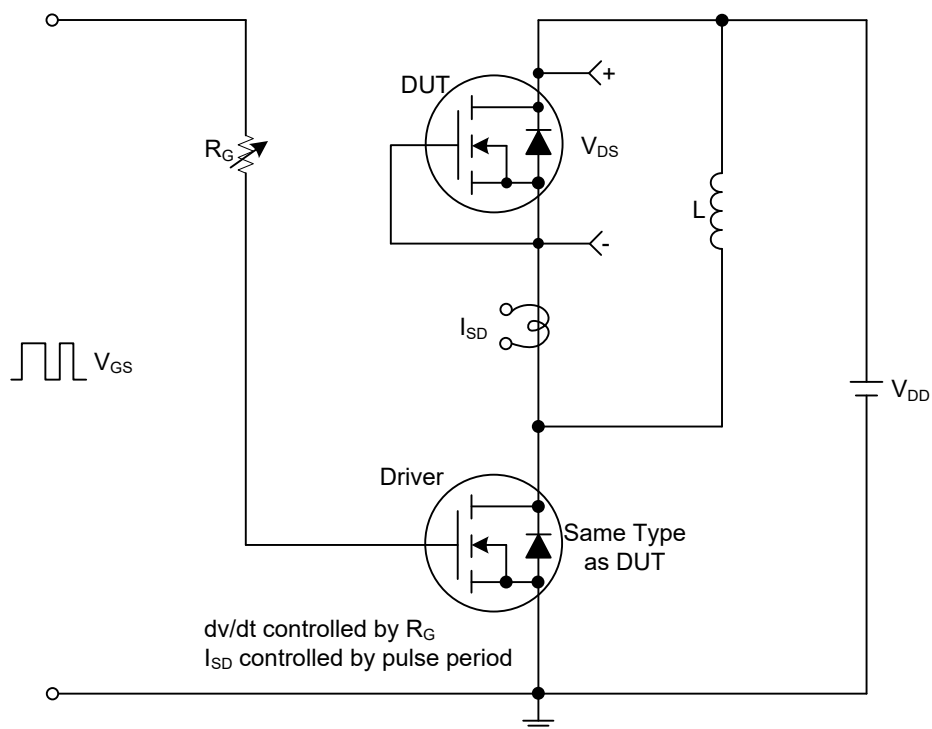
■ ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =250μA	40			V
Drain-Source Leakage Current	I _{DSS}	V _{DS} =40V, V _{GS} =0V			1	μA
Gate-Source Leakage Current	I _{GSS}	V _{GS} =±12V			±40	nA
ON CHARACTERISTICS						
Gate Threshold Voltage	V _{GS(TH)}	V _{DS} =V _{GS} , I _D =250μA	1.0		3.0	V
Drain to Source On-state Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =12.5A			20	mΩ
		V _{GS} =4.5V, I _D =12.5A			26	mΩ
DYNAMIC PARAMETERS						
Input Capacitance	C _{ISS}	V _{DS} =25V, V _{GS} =0V, f=1.0MHz		700		pF
Output Capacitance	C _{OSS}			87		pF
Reverse Transfer Capacitance	C _{RSS}			75		pF
SWITCHING PARAMETERS						
Total Gate Charge (Note 1)	Q _G	V _{DS} =32V, V _{GS} =4.5V, I _D =25A, (Note 1, 2)		14		nC
Gate Source Charge	Q _{GS}			4.2		nC
Gate Drain Charge	Q _{GD}			7		nC
Turn-ON Delay Time (Note 1)	t _{D(ON)}	V _{DD} =20V, V _{GS} =10V, I _D =25A, R _G =3Ω (Note 1, 2)		4		ns
Turn-ON Rise Time	t _R			17		ns
Turn-OFF Delay Time	t _{D(OFF)}			20		ns
Turn-OFF Fall-Time	t _F			19		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS						
Maximum Continuous Drain-Source Diode Forward Current	I _S				25	A
Maximum Pulsed Drain-Source Diode Forward Current	I _{SM}				50	A
Drain-Source Diode Forward Voltage (Note 1)	V _{SD}	I _S =25A, V _{GS} =0V			1.4	V
Reverse Recovery Time (Note 1)	t _{rr}	I _S =25A, V _{GS} =0V,		42		ns
Reverse Recovery Charge	Q _{rr}	dl/dt=40A/μs		25		nC

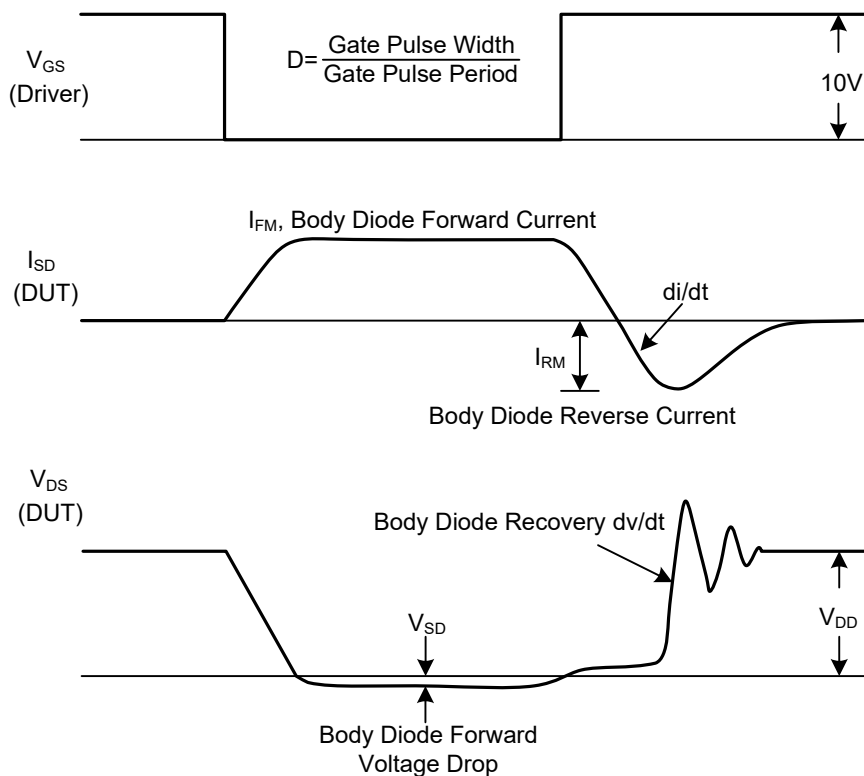
Notes: 1. Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$.

2. Essentially independent of operating ambient temperature.

■ TEST CIRCUITS AND WAVEFORMS



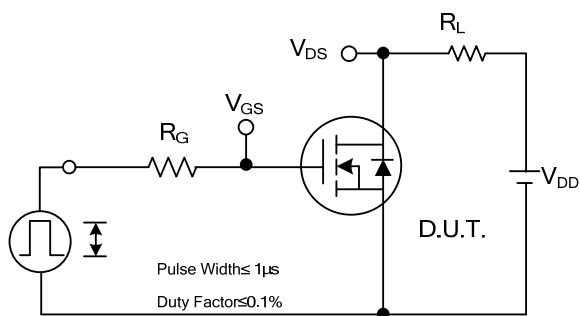
Peak Diode Recovery dv/dt Test Circuit



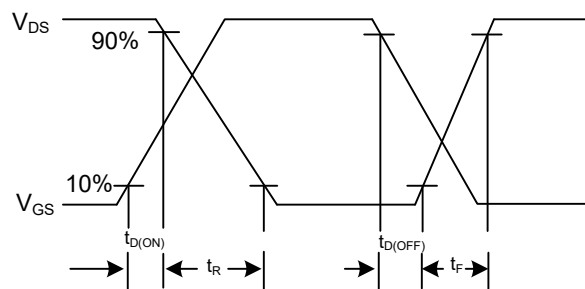
Peak Diode Recovery dv/dt Test Circuit and Waveforms

Peak Diode Recovery dv/dt Waveforms

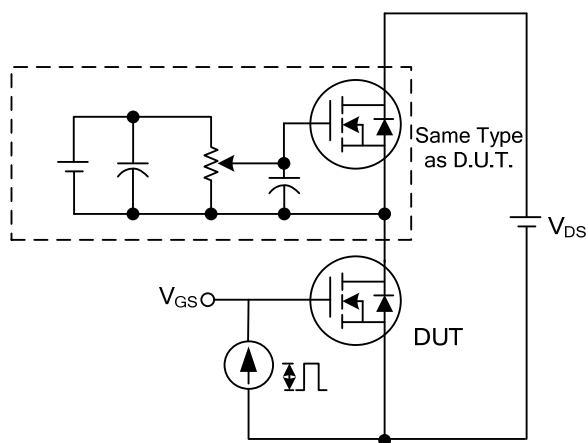
■ TEST CIRCUITS AND WAVEFORMS



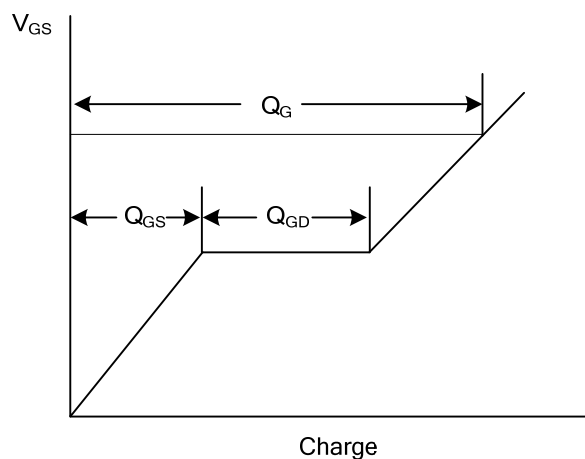
Switching Test Circuit



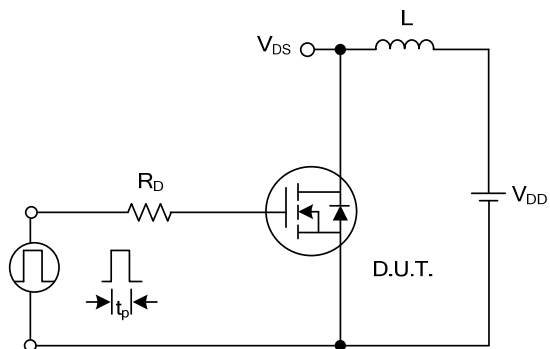
Switching Waveforms



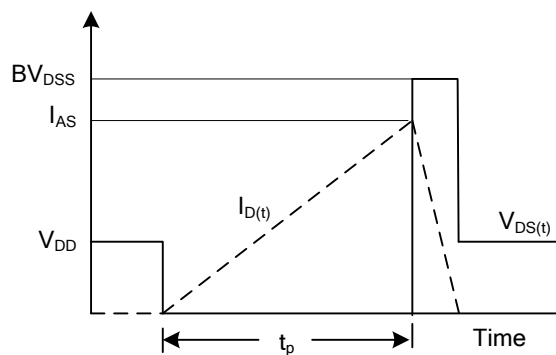
Gate Charge Test Circuit



Gate Charge Waveform

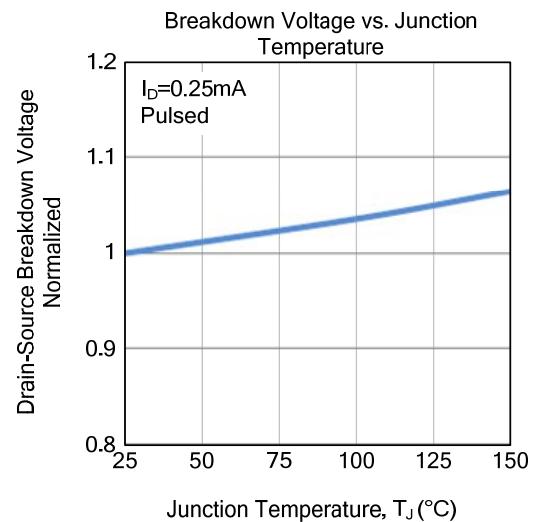
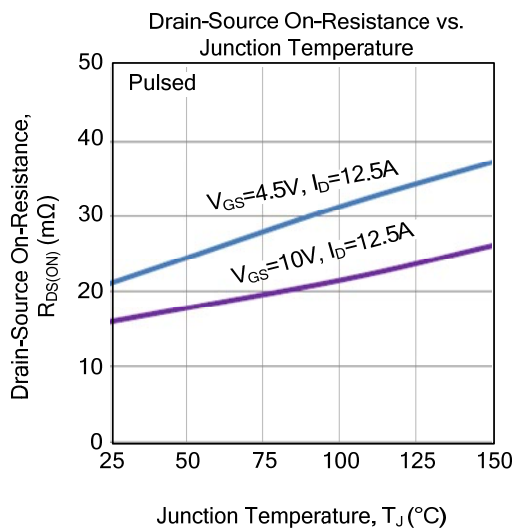
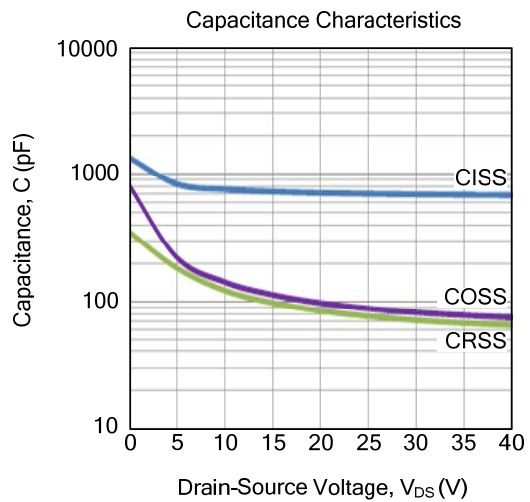
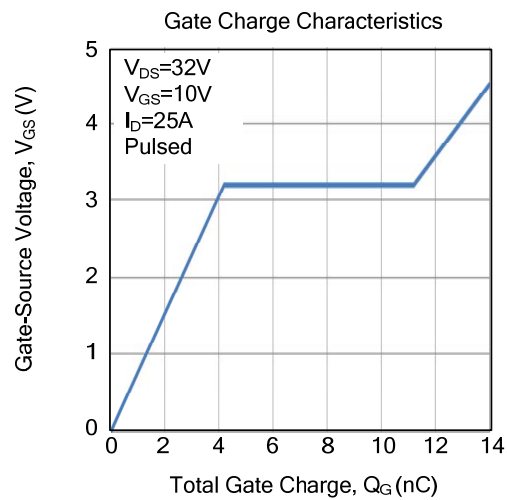
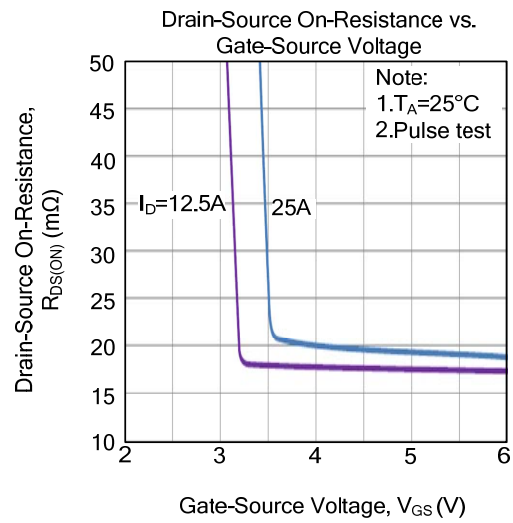
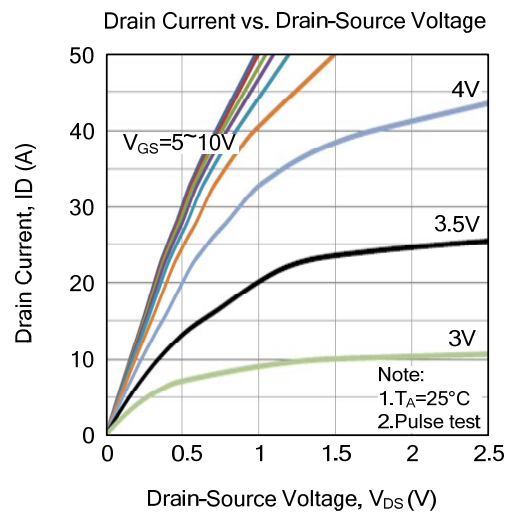


Unclamped Inductive Switching Test Circuit

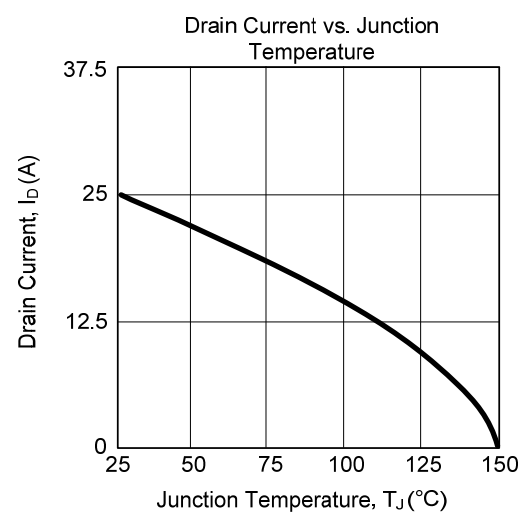
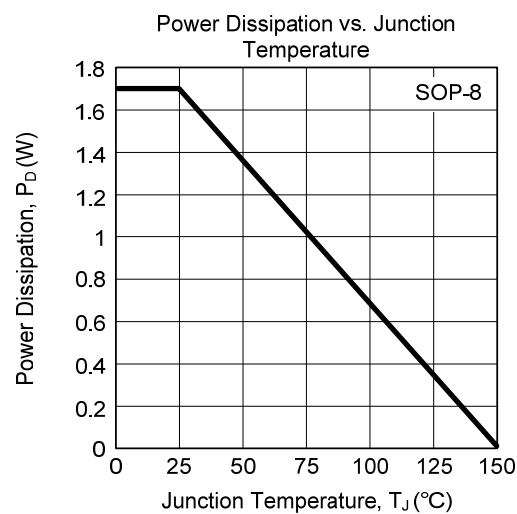
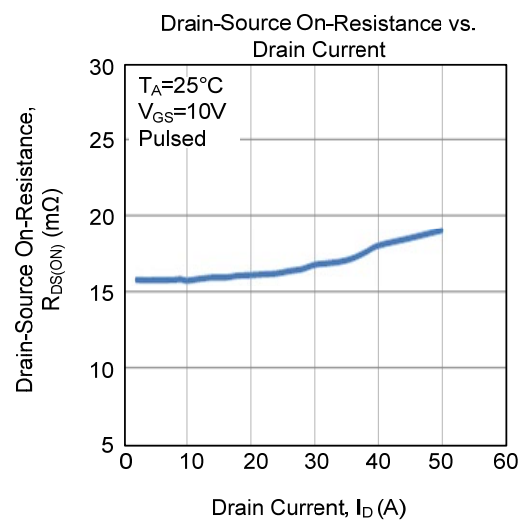
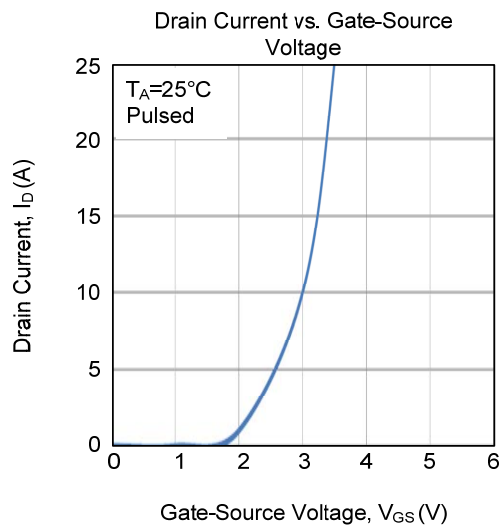
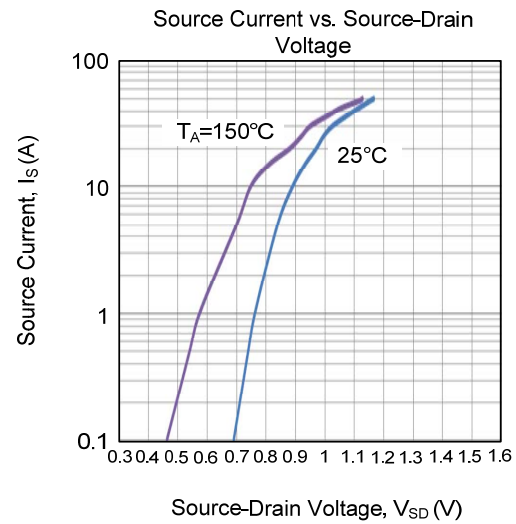
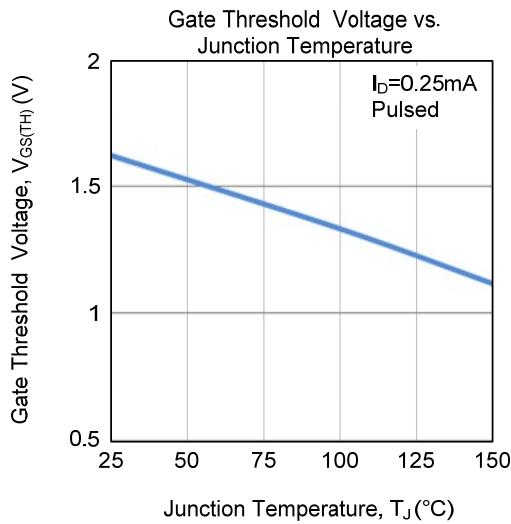


Unclamped Inductive Switching Waveforms

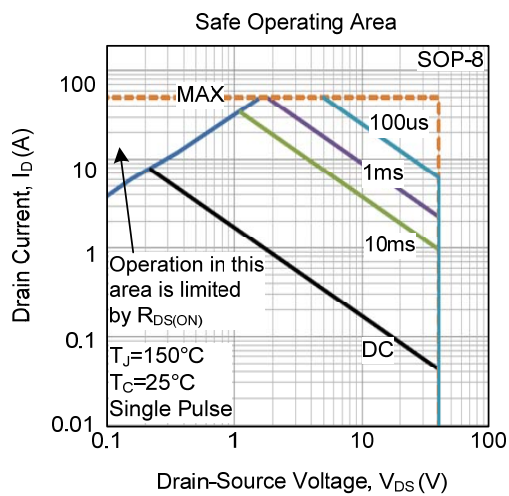
TYPICAL CHARACTERISTICS



■ TYPICAL CHARACTERISTICS (Cont.)



■ TYPICAL CHARACTERISTICS (Cont.)



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